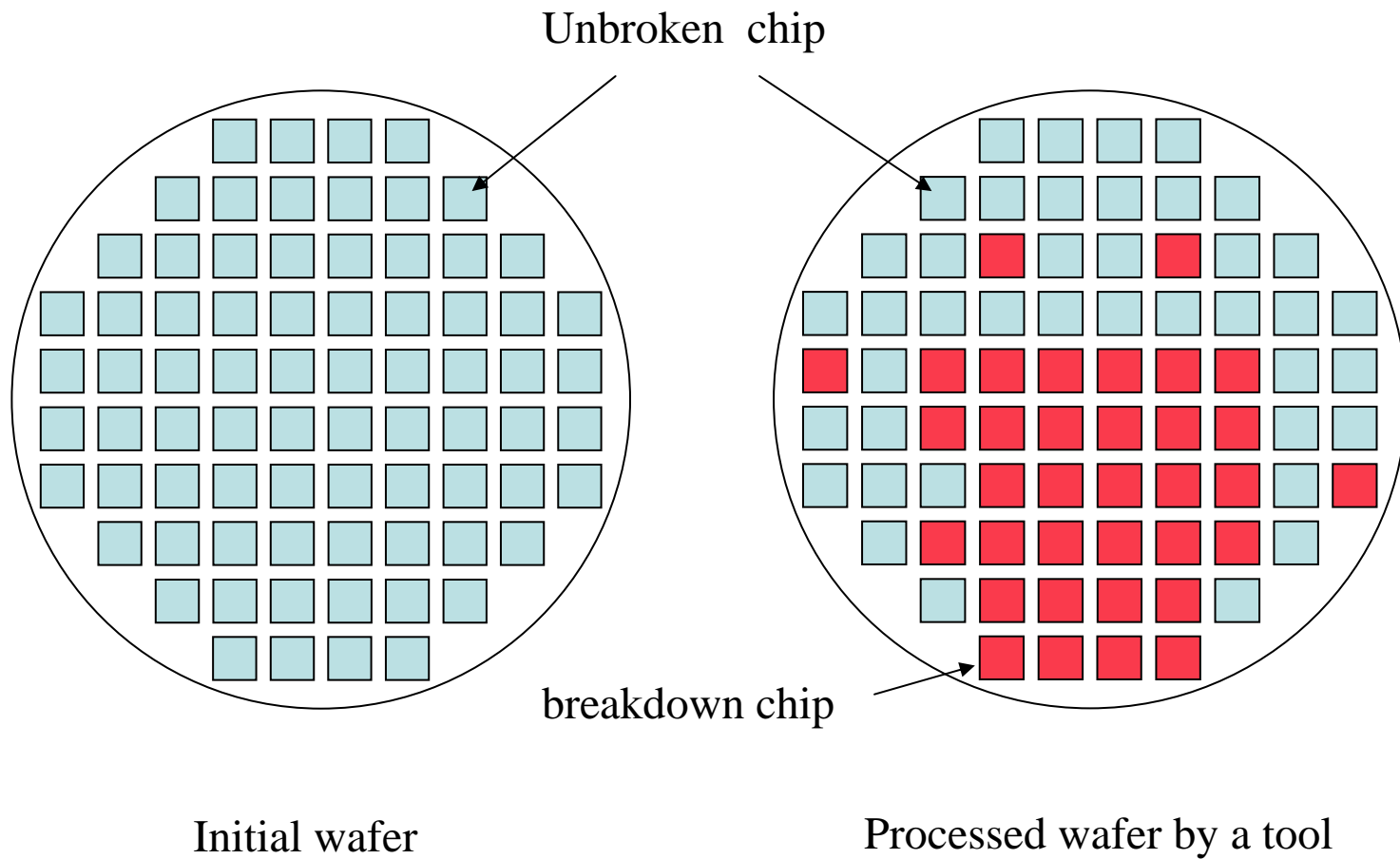


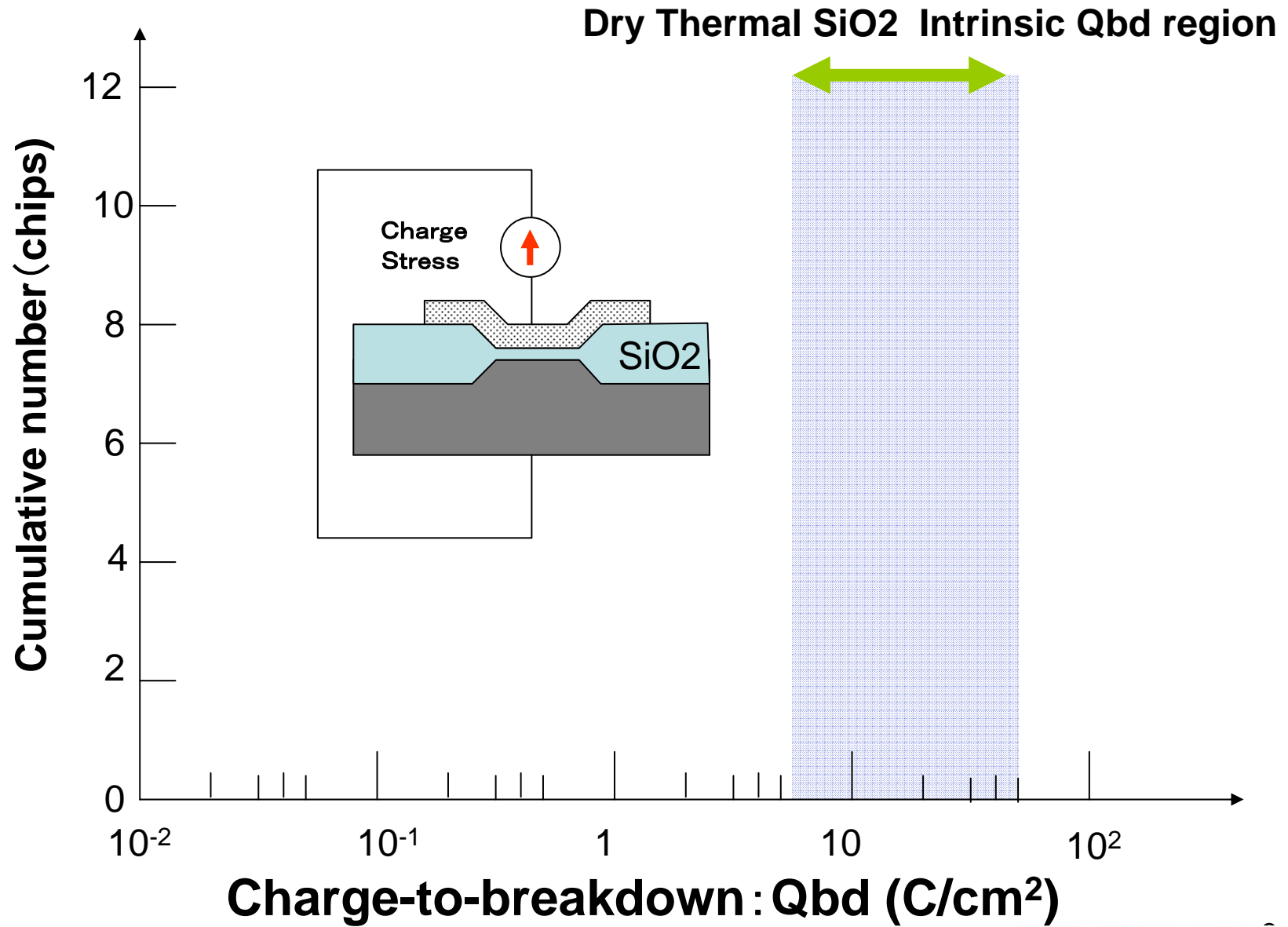
**Charge-up damage Monitor TEG
for Process Yield Security**

YST

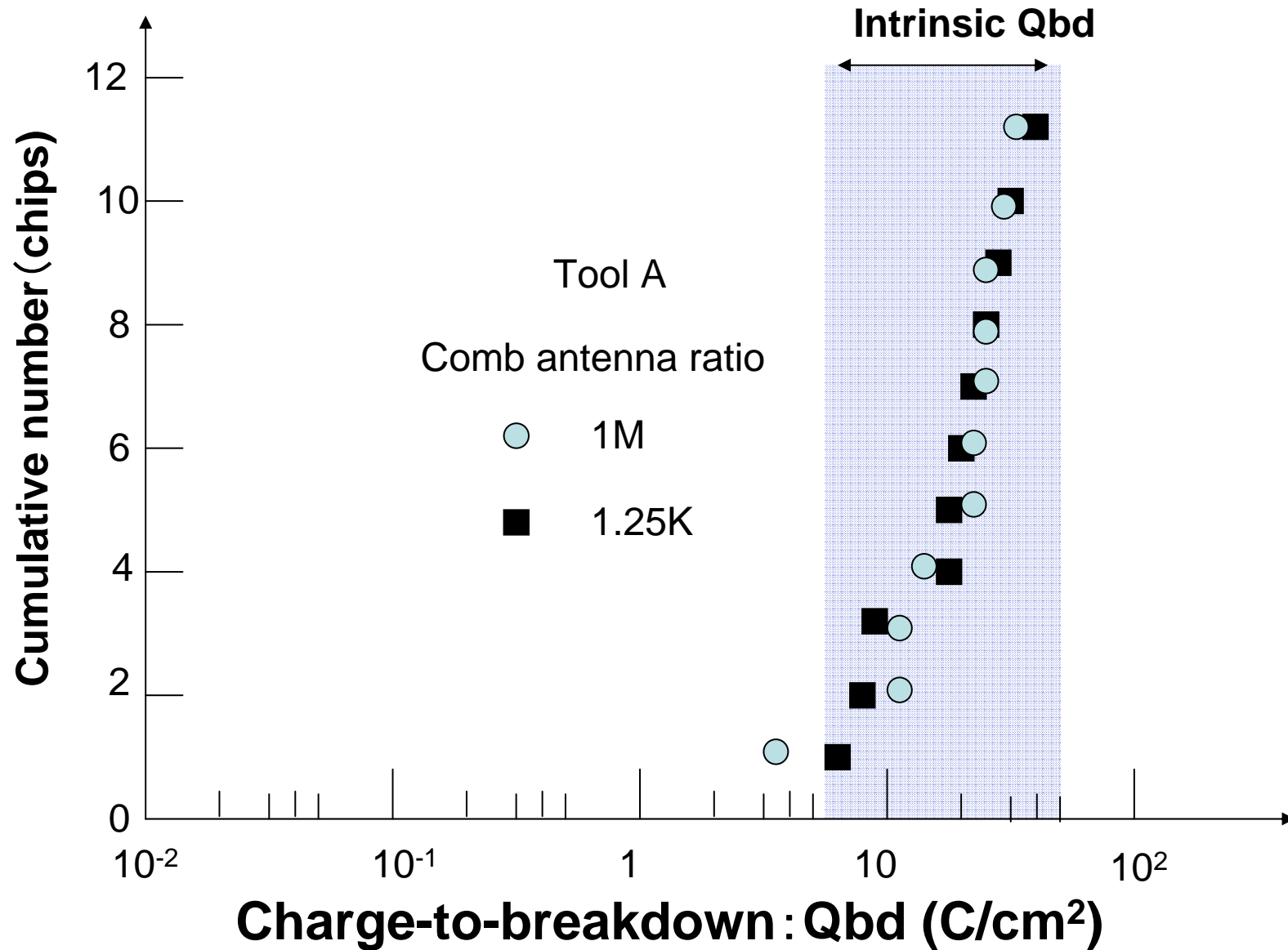
Philtech Inc.

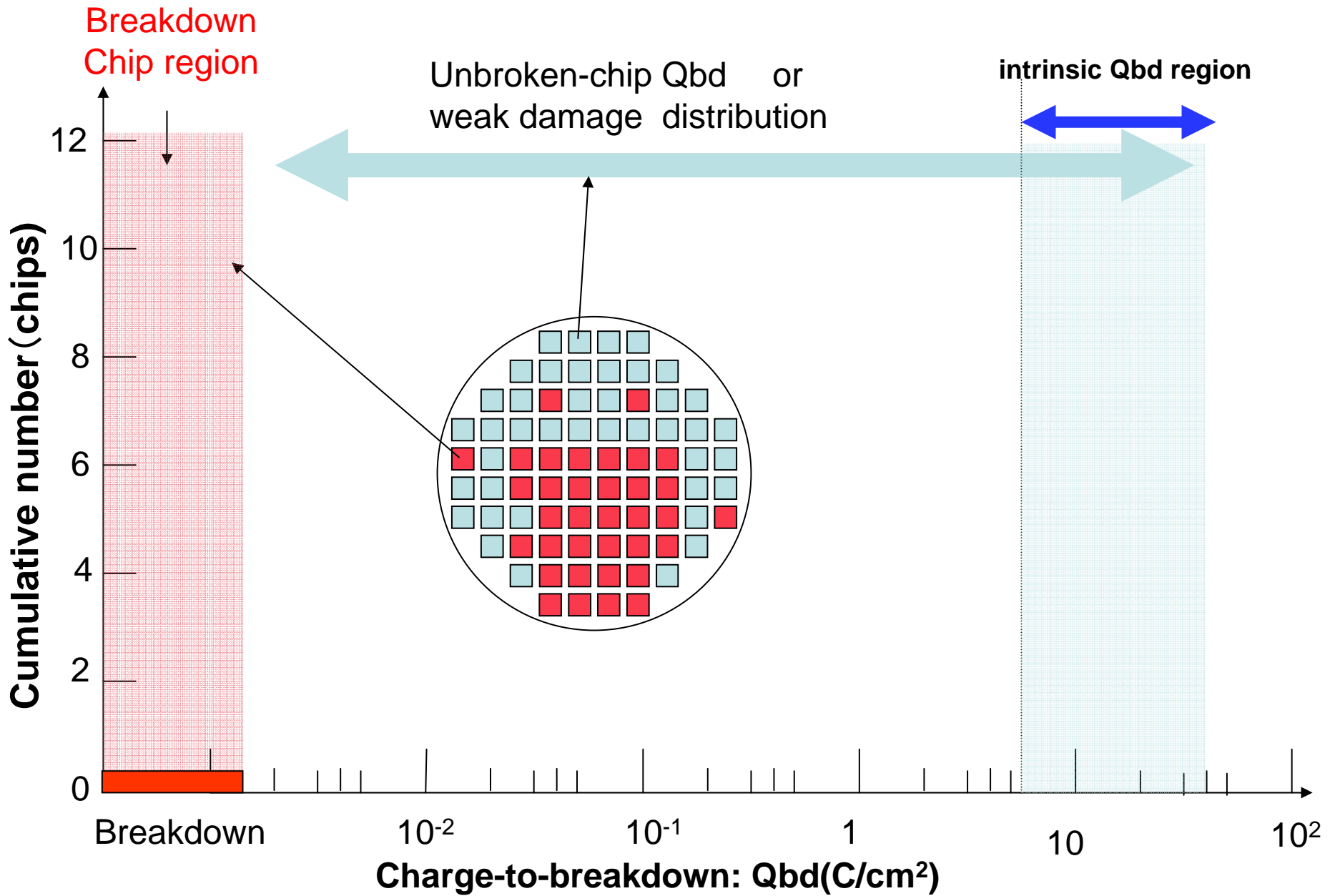


Service by YST: breakdown chip map

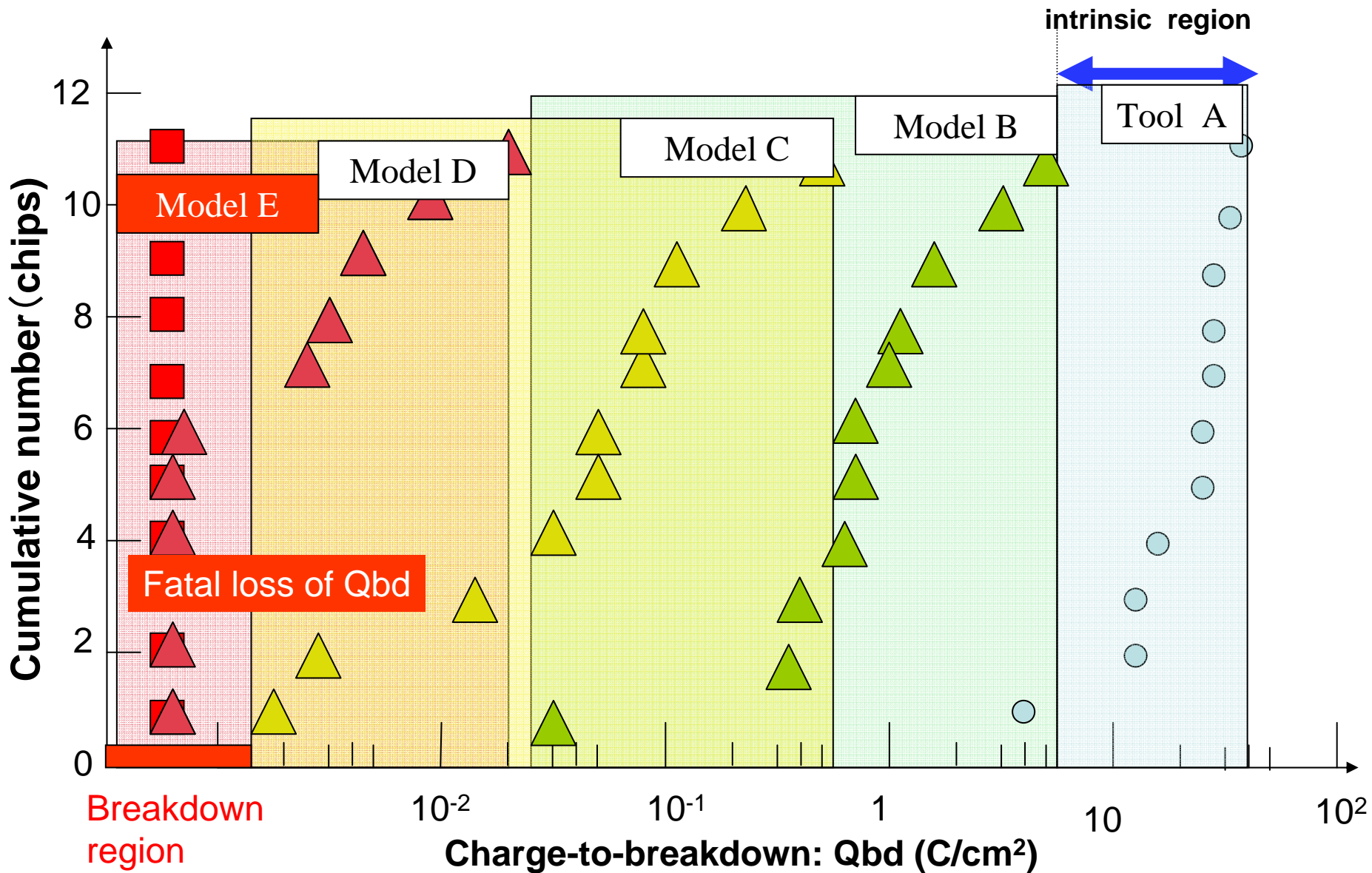


Service by YST: Measured Qbd as a damage figure





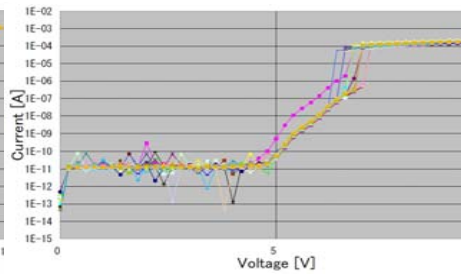
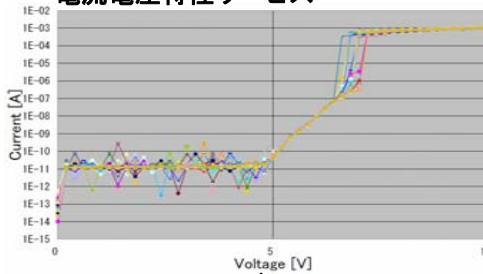
Qbd loss as a damage figure by Philtech 300mm YST



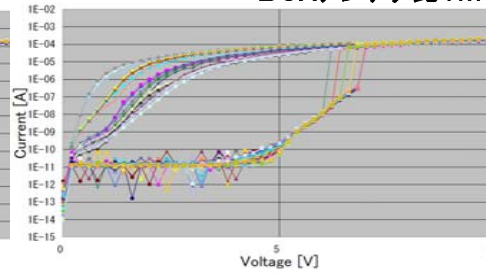
フィルテックのチャージダメージ評価サービスメニュー

ダメージ信頼性の装置性能比較の評価

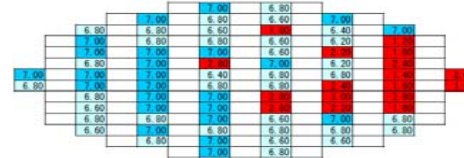
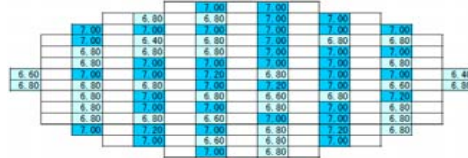
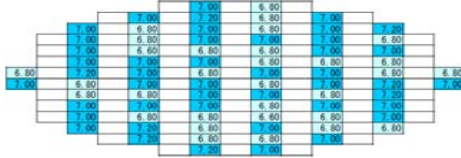
電流電圧特性サービス



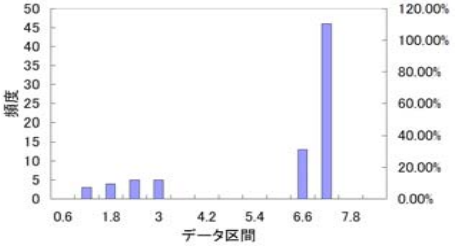
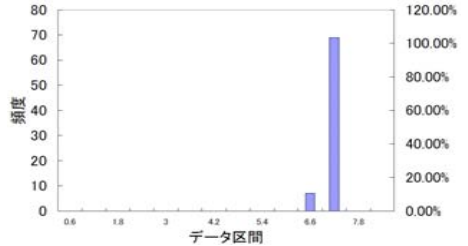
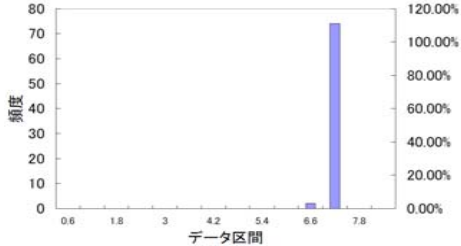
BOXアンテナ比1M



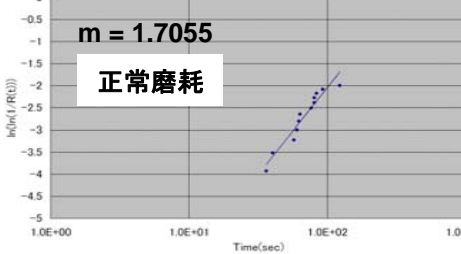
Wafer mapサービス



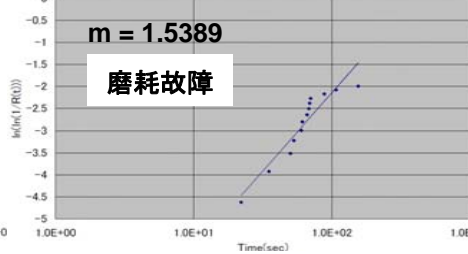
Histogramサービス



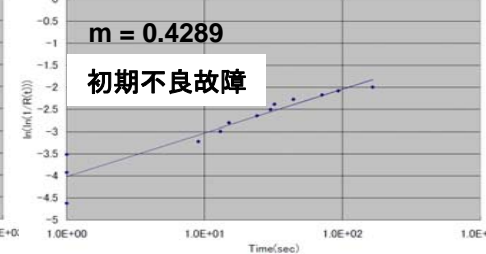
Weibull Distributionサービス (10nA/4um² ストレスで故障を発生させ装置のワイブル係数mの実力を表示)



(1) Initial Wafer



(2)プラズマ処理(by装置a)

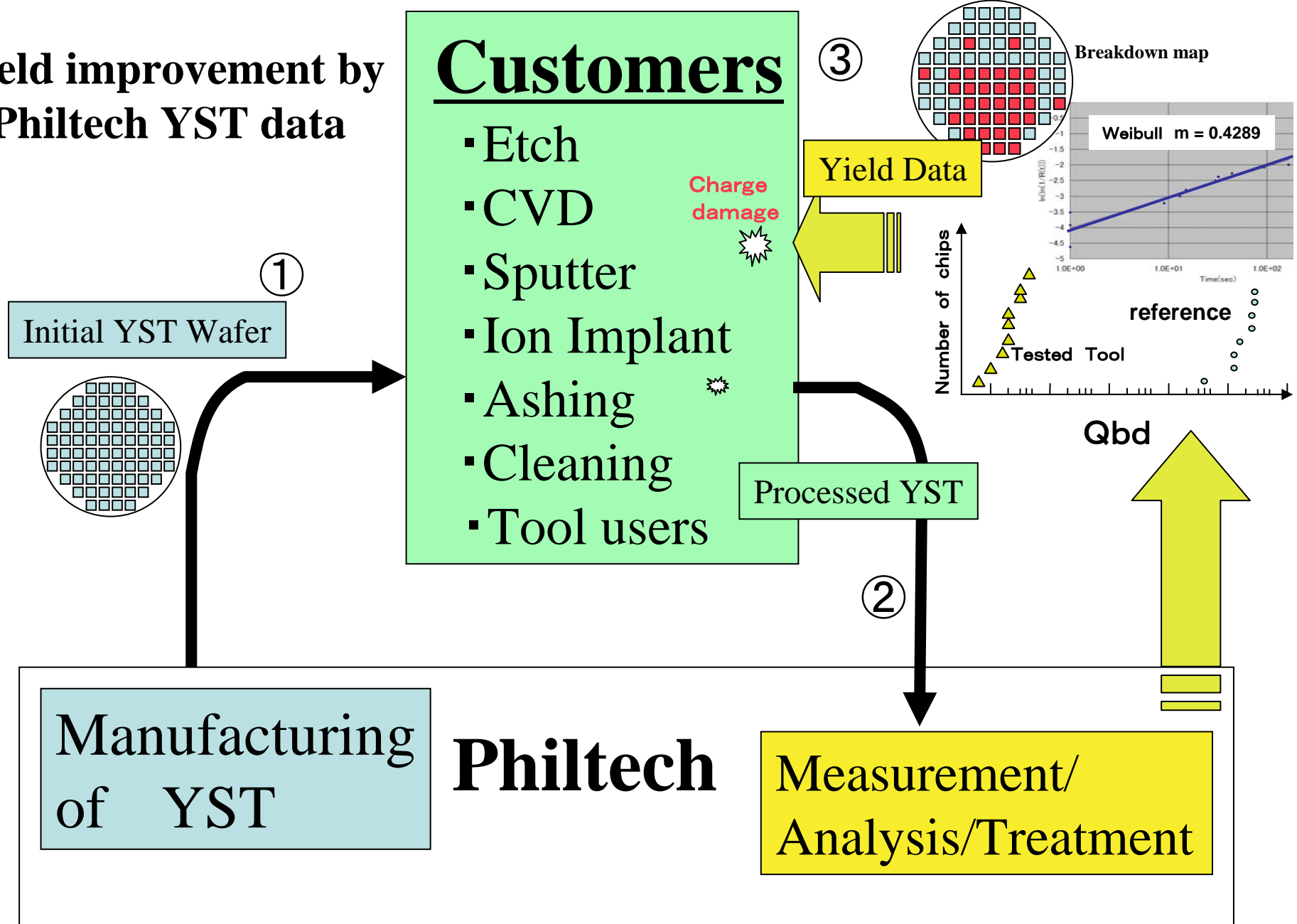


(3)プラズマ処理(by装置b)

ウエハからデータまでワンストップソリューション!

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Yield improvement by Philtech YST data



Manufacturing of YST

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